Figure 3. Unit stereographic sector showing by the open symbols the measured angles $(\theta, \varphi)$ of all new facets of 30 individual half-sphere SiGe islands on Si(001) substrate grown at 900°C as derived from the surface orientation maps exemplified in Fig. 2. Full yellow circles mark the average $(\theta, \varphi)$ values for each facet group. The previously reported dome and barn facets of $\{105\}$, $\{113\}$, $\{15\,3\,23\}$ and $\{111\}$ are indicated by the red squares. The AFM insert at the top illustrates the stereographic projection of the normal vector and its relation to the $(\theta, \varphi)$ angles for the case of a SiGe dome island.